

Test&Measurement

	YOKOGAWA AQ6361 700-1700 min HIGH PERFORMANCE MODEL
 STATUS REMOTE SWEEP ERROR 	CALIBRATION OUTPUT Image: Comparison of the state of the



The ideal OSA for optical device production

AQ6361 Optical Spectrum Analyzer



Precision Making

Bulletin AQ6361-01EN

The rapid adoption of AI is revolutionizing business, education, and communication, reshaping the way we interact and work. This transformation is driving an unprecedented demand for AIdedicated data centers, which require cutting-edge infrastructure to handle massive data processing at lightningfast speeds.

To support this acceleration, highperformance optical modules and devices are essential, ensuring seamless data transmission and maximizing data center efficiency.

At the heart of optical network testing, an optical spectrum analyzer is a critical tool for evaluating optical communication systems and components.

The AQ6361 Optical Spectrum Analyzer is designed to meet the demands of modern production environments, offering exceptional measurement speed, space efficiency, and superior optical performance – delivering the precision and reliability that customers need.

Performance – To keep up with everevolving technology, we provide worldclass optical performance and contribute to solving our customers' challenges.

Reliability – Our superior optical performance and quality have been adopted by customers worldwide.

Technical expertise – For over 40 years, our team of specialists has been listening to our customers' needs and providing solutions to their measurement challenges.

New Standard

Reduction of Production

Test Time

Measurement speed up to 20 times faster than conventional models

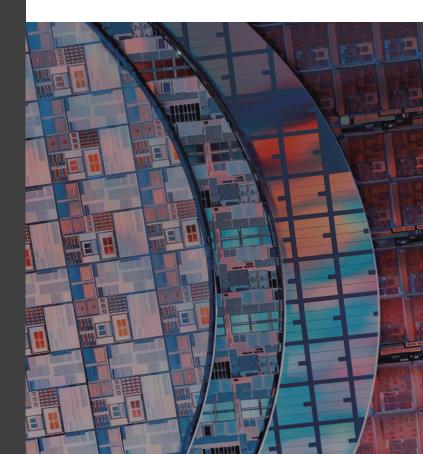
Space-saving

Two units can be mounted on one rack level

Adaptable to Various optical devices

High optical performance

- Wavelength resolution:
 0.05 nm (Standard model)
 0.03 nm (High performance model)
- Wavelength range: 1200 to 1700 nm (SW type) 700 to 1700 nm (EW type)
- Wavelength accuracy: ±0.02 nm
- Level range: +20 to -80 dBm



s for Production OSA



AQ6361 Optical Spectrum Analyzer

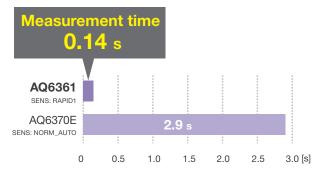
RESEREES

New Standards for Production OSA

Reduction of Production Test Time

Acceleration of Measurement Speed

With the inclusion of the sensitivity mode [RAPID] specialized for CW light, measurements can be performed up to 20 times faster compared to our previous models. This will shorten the time required for optical spectrum measurement and improve your production efficiency.



Comparison with Our Conventional Model

Reference values with a span of 100 nm, 25001 sample points, avg. 1 and a noise level of approx. –60 dBm $\,$

Integration with External Devices

Supports input and output of trigger signals. It allows for measurements synchronized with external trigger signals and output of sweep states. Synchronization and automatic control with other devices are possible. Additionally, it supports digital I/O.

Optimization of Production Line Operations

Supports Both On-Site Operation and Remote

By connecting an external monitor and mouse, it can be operated directly on-site.

Additionally, the web server function allows the AQ6361 connected to the network to be remotely controlled and monitored without the need for software.



Maintaining High Wavelength Accuracy

The AQ6361 is equipped with a wavelength calibration function that automatically corrects wavelength errors caused by changes in the operating environment. While wavelength calibration can be performed using an external light source, it can be done more easily by incorporating the optional built-in wavelength calibration light source.



Cost Reduction in Production Line Design

Space Optimization of Production Lines

Reduced to less than half the size of the AQ6370E, it can be mounted in pairs on a standard rack. This contributes to space optimization by reducing the volume used in complex production lines and chip testers.



AQ6361

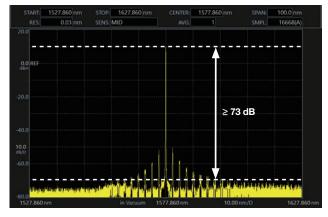
AQ6370E

High Compatibility with Remote Commands

Equipped with an Ethernet port and GP-IB (optional). The standard remote commands comply with SCPI (Standard Commands for Programmable Instruments) according to IEEE-488.2. It is compatible with both our previous AQ6370/ AQ6380 series and AQ6317 series, making it easy to transition from existing systems. Control via LabVIEW®, MATLAB[®], and Python is also possible.

Adaptable to Various Optical Modules

Depending on the measurement application, you can select a wavelength resolution from 0.03 nm (high performance model) to 2 nm. Additionally, the AQ6361 provides high dynamic range measurements with excellent stray light suppression performance of 73 dB (high performance model).



Spectrum of ITLA

Compatible with Single-mode and **Multi-mode Fibers**

Adopts a free-space structure in the optical input, compatible with single-mode and multi-mode fibers, as well as largecore fibers. Both PC connectors and Angled PC connectors can be used. Therefore, the AQ6361 can be used even if the type of optical fiber connected changes.

Program-Free Data Analysis Function

It incorporates analysis functions for evaluating the optical spectral characteristics of various devices and systems. Since programming for analysis is not required, the design time of the production line can be shortened.

Main Analysis Functions

- SMSR • WDM (OSNR)
- DFB-LD • EDFA (Gain and NF)
- iTLA • Spectrum width, etc.

Measurement applications

The AQ6361 is suitable for the evaluation and inspection of various optical components and optical devices.

- LD chip
- Optical transceiver WSS (Wavelength Selective Switch) • EDFA (Er Doped Fiber Amplifier)
- DFB-LD
- Optical filter ITLA
- WDM system

Spatial Light Measurement for LD Chips

The free-space structure of the AQ6361 can be used with both single-mode and multi-mode fibers. It can efficiently capture laser beams spatially output from wafers, LD chips, and TOSAs using multi-mode fibers with a large core diameter.

Evaluation of Optical Spectrum for High-Performance Optical Devices

High-performance optical devices, such as ITLAs, require high-performance measurement instruments to evaluate their performance. The AQ6361, with its high wavelength resolution and wavelength accuracy, can be used to evaluate high-performance optical devices.







LED indicator

LED indicators to check the status of the sweep and other conditions.

Light source output

The output section of the reference light source (optional) used for alignment adjustments and wavelength calibration. The type of connector can be changed using a separately sold connector adapter.

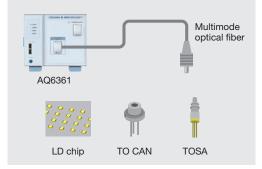
3 **Optical input**

> The measured light is input using an optical fiber cable. The type of input connector can be changed using a separately sold connector adapter.

USB

Support a USB data storage device, mouse, and keyboard.

Ethernet (10/100/1000BASE-T) Network interface for remote control, data transfer, and firmware update.



Spatial light measurement for LD chips

Digital I/O 6

This terminal can handle input and output for measurement start notifications.

7 **Trigger Input and Output**

Pulse light measurement and other measurements can be performed using an external trigger signal.

Analog output

Output an analog voltage according to the optical spectrum intensity for the stability test.

GP-IB (option)

Network interface for remote control.

10 Video Output (VGA)

Output the instrument screen to an external monitor.

Specifications

Model Wavelength range'' Span'' Wavelength accuracy''.'2 Wavelength linearity''.'2.' Wavelength repeatability Wavelength resolution be accuracy''.'2 Min. sampling resolution Number of sampling	3 *1, *2 etting*1, *2	Standard model (-10) SW type: 1200 to 1700 nm EW type: 700 to 1700 nm SW type: 0.1 nm to 500 nm, 0 nm EW type: 0.1 nm to 10 ±0.02 nm (1520 to 1580 nm), ±0.04 nm (1580 to 1620 nm) ±0.1 nm (Full range) ±0.02 nm (1520 to 1580 nm), ±0.04 nm (1580 to 1620 nm) ±0.02 nm (1520 to 1580 nm)				
Span ^{*1} Wavelength accuracy ^{*1,*2,*} Wavelength linearity ^{*1,*2,*} Wavelength repeatability Wavelength resolution be accuracy ^{*1,*2} Min. sampling resolution	3 *1, *2 etting*1, *2	SW type: 0.1 nm to 500 nm, 0 nm EW type: 0.1 nm to 10 ±0.02 nm (1520 to 1580 nm), ±0.04 nm (1580 to 1620 nm) ±0.1 nm (Full range)	±0.02 nm (1450 to 1620 nm)			
Wavelength accuracy ^{1, 2} Wavelength linearity ^{1, 2, 4} Wavelength repeatability Wavelength resolution so Wavelength resolution be accuracy ^{1, 2} Min. sampling resolution	3 *1, *2 etting*1, *2	±0.02 nm (1520 to 1580 nm), ±0.04 nm (1580 to 1620 nm) ±0.1 nm (Full range)	±0.02 nm (1450 to 1620 nm)			
Wavelength linearity ^{1, 2, 1} Wavelength repeatability Wavelength resolution so Wavelength resolution be accuracy ^{1, 2} Min. sampling resolution	3 *1, *2 etting*1, *2	±0.1 nm (Full range)				
Wavelength repeatability Wavelength resolution se Wavelength resolution be accuracy ^{1, 2} Min. sampling resolution	etting ^{*1, *2}					
Wavelength resolution se Wavelength resolution be accuracy ^{1, 2} Min. sampling resolution	etting ^{*1, *2}	±0.02 nm (1520 to 1580 nm, 1580 to 1620 nm)	±0.02 nm (1450 to 1520 nm, 1520 to 1580 nm, 1580 to 1620 nm			
Wavelength resolution ba accuracy ^{1, 2} Min. sampling resolution		±0.01 nm (1 minute)				
accuracy ^{*1, *2} Min. sampling resolution	andwidth	0.05, 0.1, 0.2, 0.5, 1 and 2 nm 0.03, 0.05, 0.1, 0.2, 0.5, 1, and 2 nm				
	anawiatii	±5% (1450 to 1620 nm, Resolution setting: 0.1 to 2 nm, At the calibration wavelength during user resolution calibration with an external DFB-LD)				
Number of sampling	M	0.001 nm				
		101 to 200001, AUTO				
Level sensitivity	TRAD mode	NORM_HOLD, NORM_AUTO, NORMAL, MID, HIGH1, HIGH2				
setting ^{*4}	RAPID mode	RAPID1 to 6				
Level sensitivity ^{*2, *5, *6, *7}	TRAD mode	SW type: -80 dBm (1300 to 1620 nm)				
	(Sensitivity: HIGH2)	EW type: -80 dBm (1300 to 1620 nm), -60 dBm (750 to 850 nm), -65 dBm (850 to 900 nm), -70 dBm (900 to 1300 nm)				
	RAPID mode (Sensitivity: RAPID6)	SW type: –73 dBm (1300 to 1620 nm) EW type: –73 dBm (1300 to 1620 nm), –53 dBm (750 to 850 nm), –58 dBm (850 to 900 nm), –63 dBm (900 to 1300 nm)				
Maximum input power*2,	*5	+20 dBm (per channel, full range)				
Maximum safe input pov	ver ^{*2, *5}	+25 dBm (total input power)				
Level accuracy ^{*2, *5, *6, *8}		±0.5 dB (1310/1550 nm, input level: -20 dBm, sensitivity: I	NORMAL, MID, HIGH1 to 2, RAPID4 to 6)			
Level flatness ^{*2, *5, *8}		±0.2 dB (1520 to 1580 nm, 1580 to 1620 nm)	±0.2 dB (1450 to 1520 nm, 1520 to 1580 nm, 1580 to 1620 nm			
Level linearity ^{*2, *5}		±0.1 dB (input level: -50 to +10 dBm, sensitivity: MID, HIG				
Polarization dependence	*2, *5, *8	±0.1 dB (1310/1550 nm)				
Stray-light suppression r		_	73 dB			
	Res.: 0.03 nm	_	50 dB (peak ±0.2 nm), 37 dB (peak ±0.1 nm)			
	Res.: 0.05 nm	65 dB (peak ±1.0 nm), 61 dB (peak ±0.4 nm), 45 dB (peak				
-	Res.: 0.1 nm	55 dB (peak ±0.4 nm), 40 dB (peak ±0.2 nm)				
Applicable fiber		SM (9.5/125), MM (GI 50/125, GI 62.5/125, Large-core: up to 200 µm)				
Optical connector		Optical input: AQ9447 (□) Connector adapter (option) required, Calibration output: AQ9441 (□) Connector adapter (option, L1 spec. only) required, NA conversion adapter: 735385 [option, AQ9447 (FC) use only] □: Connector type FC or SC				
Built-in Calibration light	source	Wavelength reference source (For optical alignment adjustments required, L1 spec. only)				
Sweep time*1, *7, *10	TRAD mode	NORM_AUTO: 0.2 s, NORMAL: 0.5 s, MID: 1 s, HIGH1: 2.4	5 s, HIGH2: 10 s			
	RAPID mode	0.2 s (sensitivity: RAPID1, span: 100 nm, sampling points: 100001 pt, averaging times: 1)				
Optical return loss ^{*12}		35 dB typ. (with Angled PC connector)				
Warm-up time		Minimum 1 hour (After warm-up, optical alignment adjustments required)				
Electrical interface		Ethernet, GP-IB (C01 spec. only), USB, VGA output, Analog output port, Trigger input port, Trigger output port, Digital I/O port				
Remote control ¹³		Remote command control: Ethernet (TCP/IP), GP-IB (C01 spec. only), AQ6317 series compatible commands (IEEE488.1) and IEEE488.2 Web server function: Remote monitoring and control				
Data storage		Internal storage: 512 Mbytes, external storage: USB storage media (memory), Format: FAT32 File type: CSV (text), Binary, BMP, PNG, JPEG				
Dimensions		Approx. 213 (W) \times 177 (H) \times 459 (D) mm (Excluding protector and handle)				
Weight		Approx. 11 kg				
Power requirements		100 to 240 VAC, 50/60 Hz, 100 VA				
Environmental conditions		Performance guarantee temperature: +18 to +28°C, Operating temperature: +5 to +35°C, Storage temperature: -10 to +50°C, Humidity: 20 to 80% RH (no condensation), Location: Indoor use, Altitude: 2000 m				
Safety Standards		EN 61010-1				
	Laser ^{*14}	EN 60825-1: 2014+A11: 2021, IEC 60825-1: 2014, GB/T 7247.1-2024 Class1				
EMC	Emission	EN 61326-1 Class A Group 1, EN 61000-3-2, EN 61000-3-3, RCM EN 61326-1 Class A Group 1, Korea Electromagnetic Conformity Standard				
	Immunity	EN 61326-1 Table 2				
Recommended calibration	on period	1 year				

- *1: Horizontal scale: Wavelength display mode. *2: With 9.5/125 μm single mode fiber (PC polished), without NA conversion adapter, after 1 hour of warm-up
- *3: After wavelength calibration with built-in reference light source or a single longitudinal mode laser (peak level: ≥ -20 dBm, Wavelength: 1520 nm to 1560 nm and absolute wavelength accuracy ± 0.003 nm)
- *4: TRAD mode: applicable for CW light and pulsed light measurement, RAPID mode:
- applicable for CW light measurement *5: Vertical scale: Absolute power display mode, resolution setting: ≥ 0.05 nm, resolution correction: OFF.
- *6: With 9.5/125 μm single mode fiber (SSMA type in JIS C 6835, PC polished, mode field diameter: 9.5 µm, NA: 0.104 to 0.107)

*7: Pulse light measurement mode: OFF, resolution correction: OFF.

*8: 23 $\pm3^{\circ}\text{C}$ at 0.05 nm resolution setting

- *9: With He-Ne laser (1523 nm) input, 0.1 nm resolution, 1520 nm to 1620 nm, except for peak wavelength ± 2 nm
- *10: 1523 nm, high dynamic mode: SWITCH, resolution correction: OFF
- *11: Span: < 100 nm, number of sampling: 1001, average number: 1.
- *12: With Yokogawa's master single-mode fiber with angled-PC connector, without NA conversion adapter, 15 dB typ. with PC connector.
- *13: Some AQ6317 series commands may not be compatible due to changes in specifications or functions.
- *14: With built-in calibration light source
- *"Typical" or "typ." in this document means "Typical value", which is for reference, not guaranteed specification.



Complies with 21 CFR 1040.10 and 1040.11 except for conformance with IEC 60825-1 Ed. 3., as described in Laser Notice No. 56, dated May 8, 2019. 4-9-8 Myojin-cho, Hachioji-shi, Tokyo 192-8566, Japan

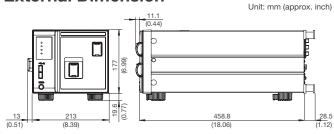
Model and Suffix Code

Model	Suffix Code	Description	
AQ6361		AQ6361 Optical Spectrum Analyz	er
Specification	-10	Standard model	
	-20	High-performance model	
Wavelength range	-SW	Standard wavelength	
	-EW	Extended wavelength	
Built-in light source	-L0	Without light source	
	-L1	Wavelength reference source	
GP-IB	-N01	No GP-IB interface included (Not for retrofitting)	
	-C01	Equipped with GP-IB interface	
Power supply code	-D	UL/CSA standard and PSE compl	liant, 125 V
	-F	VDE/Korean standard, 250 V	
	-R	Australian standard, 250 V	
	-H	Chinese standard, 250 V	
	-Q	British standard 250 V	
	-N	Brazilian standard 250 V	
	-T	Taiwanese standard 125 V	
	-В	Indian standard, 250 V	
	-U	IEC Plug Type B, 250 V	
Factory Options	/FC	AQ9447 (FC) connector adapter	For optical
	/SC	AQ9447 (SC) connector adapter	input
	/RFC	AQ9441 (FC) connector adapter	For calibration
	/RSC	AQ9441 (SC) connector adapter	output
	/NAC	735385 NA conversion adapter (F	C)

Accessories (optical)

M	odel	Suffix Code	Description
73	5371		AQ6370 Viewer (Support model: AQ6370 series, AQ6380, AQ6360 and AQ6361)
AQ9447			AQ9447 Connector Adapter
	Connector type	-FC	FC type
		-SC	SC type
AC	AQ9441		AQ9441 Connector Adapter
	Connector type	-FC	FC type
		-SC	SC type
735385			NA Conversion Adapter
	Adapter type	-001	FC connector, for GI 50/GI 62.5
75	751533 -E3		Rack mount kit (EIA, Single-housing)
		-J3	Rack mount kit (JIS, Single-housing)
75	751534 -E3		Rack mount kit (EIA, Dual-housing)
		-J3	Rack mount kit (JIS, Dual-housing)

External Dimension



Unless otherwise specified, tolerances are $\pm 3\%$ (however, tolerances are ± 0.3 mm when below 10 mm).

Optical connector adapters

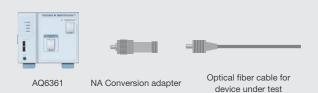


For calibration light output port AQ9441 connector adapter



NA Conversion Adapter (optional)

NA conversion adapters can be connected to GI50 or GI62.5 optical fibers with relatively large NA to improve the stability of light level measurements.



[Note]

- The stability of measurement results depends on the operating environment.
- When using NA conversion adapters, the stability of the measurement results improves as the wavelength resolution setting of the optical spectrum analyzer increases.
- When using GI62.5 and GI50 multi-mode fibers connected to NA conversion adapters, it is recommended to set the wavelength resolution of the optical spectrum analyzer to 0.2 nm or higher.

-NOTICE

- Before operating the product, read the user's manual thoroughly for proper and safe operation.
- Any company's names and product names mentioned in this document are trade names, trademarks or registered trademarks of their respective companies.

– Yokogawa's approach to preserving the global environment.

- Yokogawa's electrical products are developed and produced in facilities that have received ISO14001 approval.
- In order to protect the global environment, Yokogawa's electrical products are designed in accordance with Yokogawa's Environmentally Friendly Product Design Guidelines and Product Design Assessment Criteria.

This is a Class A instrument based on Emission standards EN61326-1 and EN55011, and is designed for an industrial environment.

Operation of this equipment in a residential area may cause radio interference, in which case users will be responsible for any interference which they cause.

YOKOGAWA

YOKOGAWA TEST & MEASUREMENT CORPORATION Global Sales Dept. /E-mail: tm@cs.jp.yokogawa.com

YOKOGAWA CORPORATION OF AMERICA

- YOKOGAWA EUROPE B.V.
- YOKOGAWA TEST & MEASUREMENT (SHANGHAI) CO., LTD. YOKOGAWA ELECTRIC KOREA CO., LTD. YOKOGAWA ENGINEERING ASIA PTE. LTD. YOKOGAWA INDIA LTD. YOKOGAWA ELECTRIC CIS LTD. YOKOGAWA AMERICA DO SUL LTDA. YOKOGAWA MIDDLE EAST & AFRICA B.S.C(c)

https://tmi.yokogawa.com/us/ https://tmi.yokogawa.com/eu/ https://tmi.yokogawa.com/cn/ https://tmi.yokogawa.com/sg/ https://tmi.yokogawa.com/in/ https://tmi.yokogawa.com/br/ https://tmi.yokogawa.com/br/ https://tmi.yokogawa.com/bh/

https://tmi.yokogawa.com/

YMI-N-MI-M-E03

The contents are as of February 2025. Subject to change without notice. Copyright © 2025, Yokogawa Test & Measurement Corporation [Ed: 01/d] Printed in Japan, 502(YMI)